

## From the Editor



## 2019 *Microscopy Today* Innovation Awards

Congratulations to the winners of the tenth annual *Microscopy Today* Innovation Awards competition. We now have honored 100 innovations over the last decade. I want to thank all of the individuals, corporations, and institutions that submitted applications to this competition. Many of those submissions, even if they did not win an Innovation Award, were subsequently published as articles within these pages. Those articles provided descriptions of devices and methods useful to microscopists—a key objective of this publication.

As always, our team of judges, led by Tom Kelly, looked for innovations that will make new scientific investigations possible. The ten winning innovations below were selected on the basis of their usefulness to the microscopy community and their probable importance for future research. The entries most likely to win are those that provide better, faster, or entirely new methods of analysis using some type of microscope or microanalytical instrument.

The 2019 *Microscopy Today* Innovation Award winners are:

**Angstrom Science, Inc.** for Access™, an ultra-thin AFM for integration with other microscopies

**Brookhaven National Laboratory, ShanghaiTech University, and City University of Hong Kong** for a compact quadrupole-based ultrafast MeV TEM

**Cornell University** for an electron microscope pixel array detector (EMPAD) for ptychography

**Gatan, Inc.** for the K3™ IS, a high-speed large-format camera for *in situ* microscopy

**Imperial College London** for nanoscale tweezers that can extract molecules from live cells

**Oak Ridge National Lab** for AICrystallographer that converts atomic images to atomic coordinates

**Protochips, Inc.** for the Atmosphere Catalysis Solution with integrated mass spectrometer

**Tomocube, Inc.** for the HT-2 holotomographic microscope with 3D fluorescence

**UCLA** for secondary electron electron-beam-induced-current (SEEBIC) imaging

**University of Illinois** for single-shot label-free autofluorescence-multiharmonic (SLAM) microscopy

An article within this issue provides descriptions of the above innovations. Nomination applications for the next competition are available upon request (charles.lyman@lehigh.edu). The deadline for application submission is March 21, 2020.

Charles Lyman  
Editor-in-Chief

**Publication Objective:** to provide information of interest to microscopists.

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